UPCOMING TTTC EVENTS

4th IEEE International Symposium on Electronic Design, Test & Applications (DELTA 08)
23-25 January 2008
Hong Kong
http://www.ece.ust.hk/delta2008
DELTA 08 is the fourth in a series of very successful workshops. Its mission is to bring together scientists, engineers, and researchers from throughout the world to discuss cutting-edge research and results in electronic design, fabrication, test, advanced-systems applications, and related areas.

9th IEEE Latin-American Test Workshop (LATW 08)
17-20 February 2008
Puebla, Mexico
http://latw.tttc-events.org
The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin America and throughout the world to present and discuss various aspects of system, board, and component testing and fault tolerance, with design, manufacturing, and field considerations in mind.

Design, Automation and Test in Europe Conference (DATE 08)
10-14 March 2008
Munich
http://www.date-conference.com
DATE is the main European event that brings together designers and design automation users; researchers; and vendors; as well as specialists in hardware and software design, test, and the manufacturing of electronic circuits and systems. DATE puts strong emphasis on ICs and SoCs, reconfigurable hardware, and embedded systems, including embedded software. This five-day event consists of a conference with plenary invited papers, regular papers, panels, hot-topic sessions, tutorials, and workshops, plus two special-focus days and a track for executives. The scientific conference is complemented by a commercial exhibition showing the state of the art in design and test tools, methodologies, IP and design services, reconfigurable and other hardware platforms, embedded software, and industrial design experiences from different application domains—for example, automotive, wireless, telecommunications, and multimedia applications.

CALL FOR PAPERS
13 IEEE European Test Symposium (ETS 08)
25-29 May 2008
Lago Maggiore, Italy
http://www.cad.polito.it/~ets08
The IEEE European Test Symposium is Europe’s premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuits and systems testing. ETS invites your participation in many aspects of testing, including mixed-signal and RF testing, nanotechnology test, and system-in-package (SiP) test. ETS 08 is organized by Politecnico di Torino and is sponsored by the IEEE Computer Society’s Test Technology Technical Council (TTTC).
Submissions deadline: 7 December 2007

NEWSLETTER EDITOR’S INVITATION
I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Bruce C. Kim, Dept. of Electrical and Computer Engineering, Univ. of Alabama, 317 Houser Hall, Tuscaloosa, AL 35487-0286; bruce.kim@ieee.org.

Bruce C. Kim
Editor, TTTC Newsletter

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